# Hill Journal of Testing Evaluation Editorial Board

## Editorial Objectives

The Journal of Testing and Evaluation is published bimonthly by ASTM, a nonprofit technical organization that develops and publishes voluntary consensus standards and related information for materials, products, systems, and services. All contributions are peer reviewed prior to publication.

The editorial objectives of this journal are to serve a broad-based audience by:

- 1. Publishing new technical information derived from the field and laboratory testing, performance, quantitative characterization, and evaluation of these materials, products, systems, and services.
- Presenting new methods and data and critical evaluations of these methods and data.
- 3. Reporting the users' experience with test methods and the results of interlaboratory testing and analysis.
- 4. Providing the scientific basis for both new and improved ASTM standards.
- 5. Stimulating new ideas in the fields of testing and evaluation.

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